Notice of References Cited Application/Control No. 10/528,328 Examiner STEVEN D. RADOSEVICH Applicant(s)/Patent Under Reexamination KAY, ANDREW Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0007108	07-2001	Teich et al.	707/200
*	В	US-7,131,115	10-2006	Hundt et al.	717/130
*	С	US-6,779,084	08-2004	Wolrich et al.	711/118
*	D	US-7,337,275	02-2008	Wolrich et al.	711/132
*	Е	US-7,337,275	02-2008	Wolrich et al.	711/132
*	F	US-2002/0027508	03-2002	Baba, Tsutomu	340/693.2
*	G	US-2002/0128994	09-2002	Sadhasivan et al.	707/1
*	Η	US-5,530,806	06-1996	Condon et al.	714/49
*	I	US-2002/0054602	05-2002	Takahashi et al.	370/412
*	J	US-5,873,097	02-1999	Harris et al.	707/203
*	К	US-5,469,562	11-1995	Saether, Christian D.	714/20
*	L	US-5,369,757	11-1994	Spiro et al.	714/19
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U	IEEE 100 The Authorative Dictionary of IEEE Standards Terms, Seventh Edition, December 2000, The Institute of Electrical and Electronics Engineering, Inc., Published by: Standards Information Network IEEE Press, page 626.		
	٧			
	w			
	×			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.